

AP20 Rec'd PCT/PTO 14 JUL 2006

**INFORMATION
DISCLOSURE STATEMENT
TRANSMITTAL**

To Commissioner For Patents

Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.

Application Number	10/586218
Filing Date	
First Named Inventor	MARINISSEN, ERIK J.
Group Art Unit	2117
Examiner Name	JAMES C KERVEROS
Atty. Docket Number	NL040065US1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number (dry "no.", "kind", if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
US-						
US-						
US-						

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number (dry "no.", "kind", if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
	1	WAAYERS T ED - INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS: "AN IMPROVED TEST CONTROL ARCHITECTURE AND TEST CONTROL EXPANSION FOR CORE-BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 2003. (ITC); CHARLOTTE NC. SEPT. 30, OCT. 2, 2003; INTERNATIONAL TEST CONF. N.Y.: IEEE US VOL. 1, 30 SEPT 2003; PP 1145-1154	
	2	ZORIAN Y ET AL: "TESTING EMBEDDED-CORE BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 1998 (IEEE CAT. NO. 98CH36270) INT. TEST CONF. WASHINGTON DC USA; ONLINE 23 OCT. 1998 (1998-10-23) PP 130-143.	

Examiner Signature	/James Kerveros/	Date Considered	05/27/2008

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST 13). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /JK/